

# IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Peter F. Symosek et al.

Examiner: unknown

Serial No. 10/718,168

Group Art Unit: unknown

Filed: November 20, 2003

Confirmation No.:

For: SIGNATURE SIMULATOR

Docket No.: H0003798 (1100.1204101)

# TRANSMITTAL SHEET

Assistant Commissioner for Patents PO Box 1450 Alexandria, VA 22313-1450

CERTIFICATE UNDER 37 C.F.R. 1.8: I hereby certify that this correspondence is being deposited with the United States

Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to the:

Commissioner for Patents, PO Box 1450, Alexandria, VA 22313-1450, on this 17th day of March, 2004.

By: John G. Shudy, Jr.

We are transmitting herewith the attached:

[X] Information Disclosure Statement, Form PTO-1449 listing a total of 4 references

with 2 non-US patent references attached.

[X] Please charge any deficiencies or credit any overpayment in the enclosed fees to

Deposit Account No. 50-0413.

John G. Shudy, Jr., Reg. No. 31,214

CROMPTON, SEAGER & TUFTE, LLC

1221 Nicollet Avenue, Suite 800 Minneapolis, Minnesota 55403-2420

Telephone: (612) 677-9050 Facsimile: (612) 359-9349





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# **INFORMATION DISCLOSURE STATEMENT (37 C.F.R. §1.97(b))**

Assistant Commissioner for Patents PO Box 1450 Alexandria, VA 22313-1450

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Commissioner for Patents, PO Box 1450, Alexandria, VA 22313-1450, on this 17th day of March, 2004.

By: John G. Shudy, Jr.

Dear Sir:

With regard to the above-identified application, the items of information listed on the enclosed Form 1449 are brought to the attention of the Examiner.

This statement should be considered because it is submitted before the mailing date of a first Office Action on-the-merits. Accordingly, <u>no fee is due</u> for consideration of the items listed on the enclosed Form 1449.

In accordance with 37 C.F. R. §1.98(a)(2), a copy of each non-US patent document or other information listed on the enclosed Form 1449 is provided.

No representation is intended to be made hereby that any of the cited references establishes, by itself or in combination with other information, a prima facie case of unpatentability of any claim of the present case.

Consideration of the items listed is respectfully requested. Pursuant to the provisions of M.P.E.P. 609, it is requested the Examiner return a copy of the attached Form 1449, marked as being considered and initialed by the Examiner, to the undersigned with the next official communication.

Respectfully submitted,

Peter F. Symosek et al.

By their attorney,

Dated:

John G. Shudy, Jr., Reg. No. 31,214

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# FORM PTO-1449 Page 1 of 1 Atty. Docket No.: H0003798(1100.1204101) Applicant: Peter F. Symosek et al. Applicant: Peter F. Symosek et al. Filing Date: November 20, 2003 U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
	5,315,513	05/1994	Abreu et al.			
	5,884,226	03/1999	Anderson et al.			

## FOREIGN PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Country	Translation Yes No
	"			

### OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	` ' 10	e Scattering and Bi-Directional Reflectance ODTRAN, SPIE Proceeding, Optical Spectroscopic eric and Space Research III, Vol. 3756, 9 pages, July		
	Polak, M.L., et al., "Passive Fourier-transform infrared spectroscopy of chemical plumes: an algorithm for quantitative interpretation and real-time background removal," Applied Optics, Vol. 34, No. 24, pp. 5406-5412, August 20, 1995.			
EXAMINE	ER:	DATE CONSIDERED:		

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.